



IEC QUALITY ASSESSMENT SYSTEM (IECQ)

covering Electronic Components,
Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Approval Independent Testing Laboratory

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Appendix-1 (50600386 ITL)

Schedule of Scope to Certificate of Approval

Test Items	Standard/Method
Scanning Electron Microscope (SEM) Analysis	TE3-F01
High Temperature Storage Life 高溫儲存試驗	JESD22-A103 (TE3-R01)
Halide/Halogen Content Test 鹵化物/鹵素含量試驗	JIS-Z-3197 8.1.4.2 (TE3-C01) IPC-TM-650 2.3.28.1 (TE3-C04) BS EN 14582 (TE3-C03)
Acid Value Test 酸價試驗	JIS-Z-3197 8.1.4.1 (TE3-C02)
Surface Insulation Resistance, Fluxes 表面絕緣阻抗試驗	IPC-TM-650 2.6.3.3 (TE3-R02)
Surface Insulation Resistance 表面絕緣阻抗試驗	IPC-TM-650 2.6.3.7 (TE3-R03)
Electrochemical Migration Resistance Test 電子遷移試驗	IPC-TM-650 2.6.14.1 (TE3-R05)
Corrosion, Flux 銅板腐蝕試驗	IPC-TM-650 2.6.15 (TE3-R04)

Technical Reviewer of DQS: _____

Date: 02/16/2023

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